

<b>Notice of References Cited</b>	Application/Control No. 10/523,168		Applicant(s)/Patent Under Reexamination KURIMURA ET AL.	
	Examiner G. Nagesh Rao		Art Unit 1722	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,471,501	10-2002	Shinma et al.	425/127
*	B	US-6,627,137	09-2003	Saito et al.	264/275
*	C	US-6,857,865	02-2005	Tsai et al.	425/116
*	D	US-6,696,220	02-2004	Bailey et al.	425/385
*	E	US-7,177,070	02-2007	Kurimura et al.	359/326
*	F	US-2001/0025001	09-2001	Oda et al.	501/32
*	G	US-6,099,771	08-2000	Hudkins et al.	264/102
*	H	US-3,987,377	10-1976	Kuroda et al.	333/151
*	I	US-6,452,306	09-2002	Inoue et al.	310/313A
*	J	US-6,031,315	02-2000	Abbott, Benjamin P.	310/313A
*	K	US-6,029,500	02-2000	Tom, Glenn M.	73/31.05
*	L	US-4,435,441	03-1984	Mariani et al.	427/10
*	M	US-2005/0019439	01-2005	Matsuki et al.	425/004.00R

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.